

**Search Notes**

Application/Control No.

10/687,424

Examiner

Kin-Chan Chen

Applicant(s)/Patent under  
Reexamination

LIAW, JHON JHY

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	700	5/12/2005	K-cc
	702		
	703		
	706		
	710		
	714		
	719		
438	724	5/12/05	K-cc

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST key words search, USPAT, US-PGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search.	5/12/2005	K-cc